

Search Notes

Application/Control No.

10/500,579

Examiner

Jinhee J. Lee

Applicant(s)/Patent under
Reexamination

HIROSHI ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	73.1	5/5/2005	LEE
✓	75R	✓	✓
✓	137R	✓	✓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
174	as above	5/5/2005	LEE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR